

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/048,146	TSANG ET AL.	
Examiner S. Devi, Ph.D.		Art Unit 1645	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	A page containing SEQ ID N: 4439 from the provisional application 60/085,598.
	V	Barrell et al., Murphy et al.. or de Virgilio et al. EMBL Z48612. Sequence alignment report (one page).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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